Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination

09/766,270

Examiner Chau Nguyen

nation SEKIDO ET AL. Art Unit

2176

**SEARCHED** 

Class	Subclass	Date	Examiner	
715	522-523	9/28/2004	CN	
715	530	9/28/2004	CN	
715	531	9/29/2004	CN	
715	539	9/29/2004	CN	
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715	522-523	11/22/2005	CN	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
East Reports	09/28/2004	CN		
	9/29/2004	CN		
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NPL Search on IEEE Database	11/23/2005	CN		